

In re application of: Michael A. Centanni et al.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE CITATION

Serial No:	10/663,593		Group No.:	1744		
Filed:	September 16,	2003	Examiner:	L.McKar	ne	
For: SENSO	OR FOR DETER	RMINING CON	CENTRATIO	ON OF FLUID	STERILAN	IT
Commissioner P.O. Box 1450 Alexandria, V				•		
		U.S. Pa	tent Docum	<u>ents</u>		
Examiner Initials	Document Number	Date	Nan	ne	Class	
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	Other Prior	Art (Inc. Autho	or, Title, Dat	e, Pertinent l	Pages, Etc.)	
Examiner		•				
<u>Initials</u>	Docun	nent				
"Quartz Micro	Steven J. Lask obalance Studie	cy, Howard R.	nd Ion Tran	sport in Thi	• •	ent of Chemistry, Films in Sensor
"Quartz Micro Applications o Reactions at Po	Steven J. Lask bbalance Studie f the QCH," <i>Tec</i> Sylvain Lazard olymer Surfaces	xy, Howard R. is of Solvent and hinical Digest 199	nd Ion Trar 90, pages 1-4 Granier, "Ex th a Quartz-0	sport in Thi cimer Laser Crystal Microl	n Polymer Light Induction	Films in Sensor eed Ablation and vember 16, 1987,
"Quartz Micro Applications of Reactions at Po J. Appl. Phys 6 "Experimental	Steven J. Lask obalance Studie f the QCH," <i>Tec</i> Sylvain Lazard olymer Surfaces i3 (6), 15 March Stanley Bruck Observations or	xy, Howard R. is of Solvent as hnical Digest 199 as Measured wi 1988, 1988 Ametenstein, C. Pa	nd Ion Tran 90, pages 1-4 Granier, "Ex th a Quartz-Cerican Institute aul Wilde, nomena Acco	isport in Thi ccimer Laser Crystal Microl ce of Physics, p Michael Sha mpanying Re	Light Induction Polymer Light Induction Polymer Dages 2110-2 y and A. dox Switchin	Films in Sensor and Ablation and vember 16, 1987, 2115. Robert Hillman, ag in Polythionine
"Quartz Micro Applications of Reactions at Po J. Appl. Phys 6 "Experimental Films Immerse	Steven J. Lask balance Studie f the QCH," Tec Sylvain Lazard olymer Surfaces 3 (6), 15 March Stanley Bruck Observations or d in Strong Acid Robert R. McC stal Microbalance	ky, Howard R. is of Solvent as hnical Digest 199 e and Vincent as Measured with 1988, 1988 Americanstein, C. Para Transport Phen I Solutions," 199 Caffrey, Stanley E	nd Ion Tran 90, pages 1-4 Granier, "Ex th a Quartz-Cerican Institution and Wilde, nomena Acco 0 American G	acimer Laser Crystal Microl te of Physics, p Michael Sha mpanying Rec Chemical Soci	Light Induction Polymer Light Induction Polymer Dages 2110-2 y and A. dox Switchinety, pages 78 Prasad, "No	Films in Sensor and Ablation and vember 16, 1987, 2115. Robert Hillman, ag in Polythionine

Other Prior Art (Inc. Author, Title, Date, Pertinent Pages, Etc.)-continued

Examiner Initials	Document
M PMMA Thin	J.A. Moore and Sang Youl Kim, "Diffusion of Small Molecules in Radiation Damaged Films," 2002 Engineering Info. Inc., pages 383-386.
	Rade Ognjanovic, CY. Hui, E.J. Kramer, "The Study of Polystyrene Surface Swelling rystal Microbalance and Rutherford Backscattering Techniques," <i>Journal of Materials</i> 990), 1990 Chapman and Hall Ltd., pages 514-518.
Organic and I	H.G. Tompkins, "Use of Surface and Thin Film Analysis Techniques to Study Metal-Metal-Polymer Interaction: A Review," <i>Thin Solid Films</i> , 119 (1984), pages 337-348.
	Sylvain Lazare, Jean Claude Soulignac and Pascal Fragnaud, "Direct and Accurate of Etch Rate of Polymer Films under Far-UV Irradiation," Appl. Phys. Lett. 50 (10), 9 1987 American Institute of Physics, pages 624-625.
Size Distribu 554.	Aljosa Vrhunec, Andreja Kolenc, Dusan Teslic, Iztok Livk and Ciril Pohar, "Crystal ion in Batch Sodium Perborate Precipitation," Acta Chim. Slov. 1999, 46(4), pages 543-
331.	
Examiner:	Date Considered:
Leigh **Examiner:	v

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For:

SENSOR FOR DETERMINING CONCENTRATION OF FLUID STERILANT

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

U.S. Patent Documents

Examiner Initials	Document Number	Date	Name	Class
LM	3,164,004	01/05/1965	King, Jr.	73/24.06
	3,327,519	06/27/1967	Crawford	73/24.06
	3,464,797	09/02/1969	Hagopain	23-232
	4,163,384	08/07/1979	Blakemore	73/29
	4,236,893	12/02/1980	Rice	23/230 B
	4,242,096	12/30/1980	Oliveira et al.	23/230 B
	4,314,821	02/09/1982	Rice	23/230 B
	4,788,466	11/29/1988	Paul et al.	310/316
	4,849,178	07/18/1989	Azuma	422/69
LM	5,339,675	08/23/1994	DiLeo et al.	73/24.040

Leigh McKara 1/12/05

-5-

LM	5,595,908	01/21/1997	Fawcett et al.	435/287.2
	5,700,375	12/23/1997	Hagen et al.	210/651
	5,756,631	05/26/1998	Grate	528/26
	5,856,198	01/05/1999	Joffe et al.	436/100
	5,866,798	02/02/1999	Schönfeld et al.	73/24.06
-	5,958,787	09/28/1999	Schönfeld et al.	436/116
	6,171,867	01/09/2001	Feucht et al.	436/124
	6,196,052	03/06/2001	May et al.	73/24.06
	6,410,332	06/25/2002	Desrosiers et al.	436/37
	6,560,551	05/06/2003	Severson et al.	702/54
LM	6,630,560	10/07/2003	McGill et al.	528/25

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